

<b>Search Notes</b> 	<b>Application/Control No.</b> 10/642,790	<b>Applicant(s)/Patent under Reexamination</b> MURAKAMI, TAKEHIKO
	<b>Examiner</b> Randall Chin	<b>Art Unit</b> 1744

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner